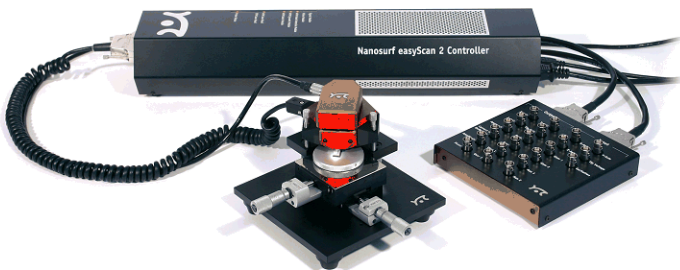
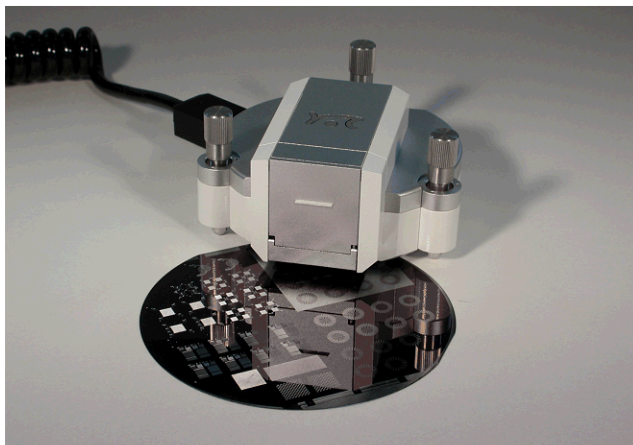


## Modular easyScan 2



## All-in-One Mobile S



## easyPLL plus Set



**Return by fax to: +49 6103 30098 29**

Early registration is encouraged

Please reply by **March 6, 2006**

Name: .....

Institution: .....

Department: .....

Address: .....

Phone: .....

Fax: .....

E-Mail: .....

I / We plan to participate in the workshop on

- Mon, March 20, 2006, Poznan
- Tue, March 21, 2006, Lodz
- Wed, March 22, 2006, Warszawa
- Thu, March 23, 2006, Lublin
- Fr, March 24, 2006, Kraków
- Sat, March 25, 2006, Wrocław

I will bring ..... colleagues with me.

I / We plan to bring with us the following sample for a test measurement:

.....  
 .....

**Further details follow with the registration acknowledgment**



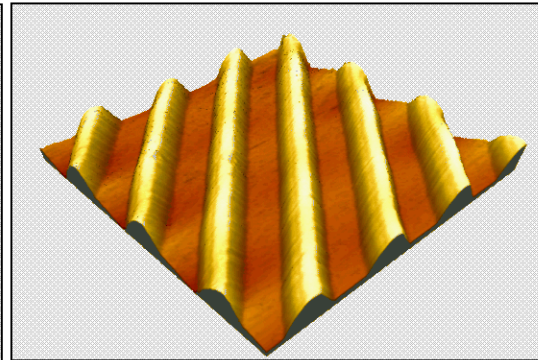
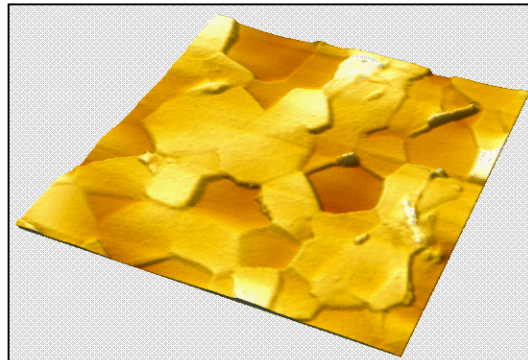
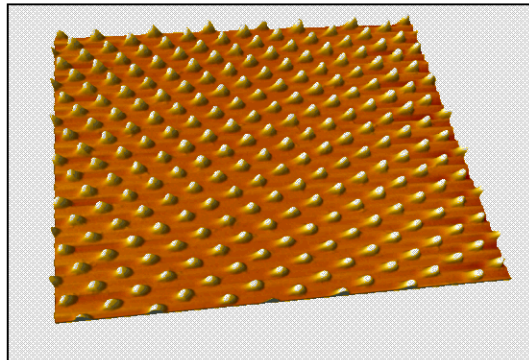
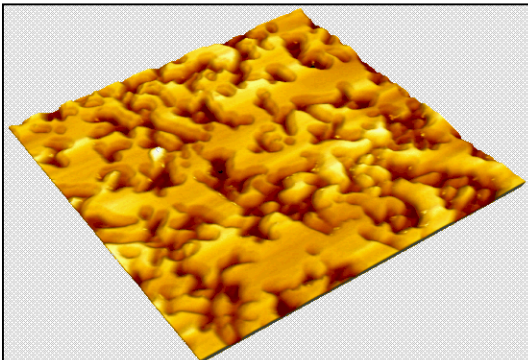
## Invitation

### SPM Road Show

March 20 – 25, 2006



**Schaefer Technologie GmbH**  
 Phone: +49 6103 30098 0  
 Fax: +49 6103 30098 29  
 E-mail: [info@schaefer-tec.com](mailto:info@schaefer-tec.com)  
 Web: [www.schaefer-tec.com](http://www.schaefer-tec.com)



## Nanosurf® Product Range:

Nanosurf AG is dedicated to making Scanning Probe Microscopes as easy and affordable to use as an optical microscope.

The modularity of the **easyScan 2 STM/AFM** series allows it to meet even apparently contradictory needs with a professional and affordable system tailored to your requirements. This makes the easyScan 2 an essential tool for teaching, training, and research.

The **Mobile S** Atomic Force Microscope makes high precision surface measurements simple and affordable, just as they should be. High-tech coatings, tiny particles, and minute surface structures can now easily be measured on site, enabling efficient, non-destructive process control without the need for highly specialised training.

The easyPLL plus FM Detector and easyPLL plus Sensor Controller make up the **easyPLL plus** set of electronics for NC-AFM/dynamic force microscopy. With new and improved features this set will take your results to new heights and make life easier. Produce higher quality images of a wider range of materials with unsurpassed ease.

**Akiyama Probe Kit** adds FM detection to existing DI Multimode™ SPM.

[www.nanosurf.com](http://www.nanosurf.com)

## Workshop Programme

We are pleased to announce the first Nanosurf® SPM roadshow/workshop in Poland.

The typical timing for this presentation is planned as follows:

20-30 min	Welcome remarks and introduction to the Nanosurf product range Martin Schaefer, Schaefer Technologie
20-30 min	easyScan 2 SPMs applied to research and education Dr. Loris Scandella, Nanosurf AG
45 min	Live tutorial and demonstration of the new <b>easyScan 2</b> SPM series and the <b>Mobile S</b> AFM system
45 min	<b>Hands-on</b> and sample measurements

**The workshop is free of charge**

## Dates & Places (tentative)

### Poznan: Monday, March 20, 2006

Adam Mickiewicz University of Poznan,  
Dept. of Solid State Physics  
Courtesy of Prof. Dr. Boguslaw Mroz

### Lodz: Tuesday, March 21, 2006

University of Lodz, Dept. of Solid State Physics  
Courtesy of Dr. Zbigniew Klusek

### Warszawa: Wednesday, March 22, 2006

Warsaw University, Dept. of Chemistry  
Courtesy of Krzysztof Miecznikowski

### Lublin: Thursday, March 23, 2006

Marie Curie-Sklodowska University Lublin,  
Institute of Physics  
Courtesy of Prof. Dr. Mieczyslaw Jalochocki

### Kraków: Friday, March 24, 2006

AGH University of Science and Technology,  
Faculty of Physics and Applied Computer Science  
Courtesy of Prof. Dr. Józef Korecki

### Wrocław: Saturday, March 25, 2006

University of Wrocław,  
Institute of Experimental Physics  
Integrated in Workshop on Surface Physics & Chemistry  
<http://wroclaw-bonn.ifd.uni.wroc.pl/index.html>  
Courtesy of Dr. Aleksander Krupski